### N-Channel Enhancement Mode Power MOSFET

### **General Description**

The HM80N08K uses advanced trench technology and design to provide excellent  $R_{\rm DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

### Features

- $V_{DS}$ =80V;  $I_D$ =80A@  $V_{GS}$ =10V;  $R_{DS(ON)}$ <8m $\Omega$  @  $V_{GS}$ =10V
- Special process technology for high ESD capability
- Special designed for Convertors and power controls
- High density cell design for ultra low Rdson
- Fully characterized Avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

## **Application**

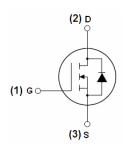
- Power switching application
- Hard Switched and High Frequency Circuits
- Uninterruptible Power Supply

### **Product Summary**

BV <sub>DSS</sub> typ.	80	٧
R <sub>DS(ON)</sub> typ.	6.5	mΩ
max.	8.0	mΩ
I <sub>D</sub>	80	Α

#### 100% UIS TESTED!





TO-252-2L top view

Schematic diagram

### **Package Marking And Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM80N08K	HM80N08K	TO-252-2L			-

### Table 1. Absolute Maximum Ratings (TA=25℃)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (V <sub>GS</sub> =0V)	V <sub>DS</sub>	80	V
Gate-Source Voltage (V <sub>DS</sub> =0V)	$V_{GS}$	±25	V
Drain Current (DC) at Tc=25℃	I <sub>D (DC)</sub>	80	Α
Drain Current (DC) at Tc=100°C	I <sub>D (DC)</sub>	60	Α
Drain Current-Continuous@ Current-Pulsed (Note 1)	I <sub>DM (pluse)</sub>	320	Α
Peak diode recovery voltage	dv/dt	30	V/ns
Maximum Power Dissipation(Tc=25℃)	P <sub>D</sub>	170	W
Derating factor		1.13	W/℃
Single pulse avalanche energy (Note 2)	E <sub>AS</sub>	580	mJ
Operating Junction and Storage Temperature Range	$T_{J}$ , $T_{STG}$	-55 To 175	$^{\circ}\!\mathbb{C}$

Notes 1. Repetitive Rating: Pulse width limited by maximum junction temperature

 $2. \text{EAS condition:} \ \ \, \text{Tj=}25\,^{\circ}\text{C}\,, \text{Vdd=}50\text{V}, \text{VG=}10\text{V}, \text{L=}0.3\text{mH}\,, \text{I}_{\text{D}}\text{=}62\text{A};}$ 

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**Table 2. Thermal Characteristic** 

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R <sub>thJC</sub>	0.88	°C/W
Thermal Resistance, Junction-to-Ambient (Maximum)	R <sub>thJA</sub>	63	°C/W

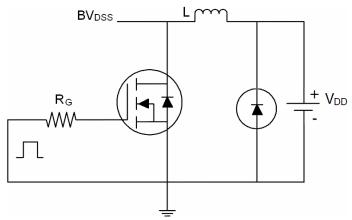
Table 3. Electrical Characteristics (TA=25℃ unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
On/off states						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA	80	84		V
Zero Gate Voltage Drain Current(Tc=25℃)	I <sub>DSS</sub>	V <sub>DS</sub> =80V,V <sub>GS</sub> =0V			1	μΑ
Zero Gate Voltage Drain Current(Tc=125℃)	I <sub>DSS</sub>	V <sub>DS</sub> =80V,V <sub>GS</sub> =0V			10	μΑ
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20V, $V_{DS}$ =0V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	2	2.85	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =40A		6.5	8	mΩ
Dynamic Characteristics						
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =30A		66		S
Input Capacitance	C <sub>lss</sub>	\\ 05\\\\ 0\\		4400		PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V,		340		PF
Reverse Transfer Capacitance	C <sub>rss</sub>	- F=1.0MHz		260		PF
Total Gate Charge	Qg	V 20VI 20A		100		nC
Gate-Source Charge	$Q_{gs}$	- V <sub>DS</sub> =30V,I <sub>D</sub> =30A,		20		nC
Gate-Drain Charge	$Q_{gd}$	- V <sub>GS</sub> =10V		30		nC
Switching times		_	•	•	•	•
Turn-on Delay Time	t <sub>d(on)</sub>			17.8		nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =30 $V$ , $I_D$ =2 $A$ , $R_L$ =15 $\Omega$		11.8		nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{G}$ =2.5 $\Omega$		56		nS
Turn-Off Fall Time	t <sub>f</sub>			14.6		nS
Source- Drain Diode Characteristics		_	•	•	•	•
Source-drain current(Body Diode)	I <sub>SD</sub>				80	Α
Pulsed Source-drain current(Body Diode)	I <sub>SDM</sub>				320	Α
Forward on voltage <sup>(Note 1)</sup>	V <sub>SD</sub>	Tj=25℃,I <sub>SD</sub> =40A,V <sub>GS</sub> =0V			1.2	V
Reverse Recovery Time <sup>(Note 1)</sup>	t <sub>rr</sub>	T:-05°0   -75^ 4:/-14 400^/			36	nS
Reverse Recovery Charge <sup>(Note 1)</sup>	Q <sub>rr</sub>	- Tj=25℃,I <sub>F</sub> =75A,di/dt=100A/μs			56	nC
Forward Turn-on Time	t <sub>on</sub>	Intrinsic turn-on time is negligible(turn-on is dominated by $L_S$ +l				y L <sub>S</sub> +L <sub>D</sub> )

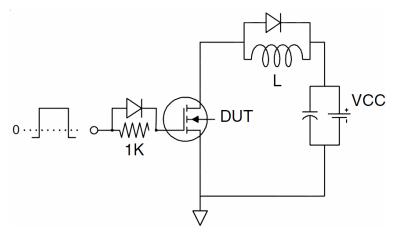
Notes 1.Pulse Test: Pulse Width ≤ 300 $\mu$ s, Duty Cycle ≤ 1.5%, R<sub>G</sub>=25 $\Omega$ , Starting Tj=25 $^{\circ}$ C

# **Test circuit**

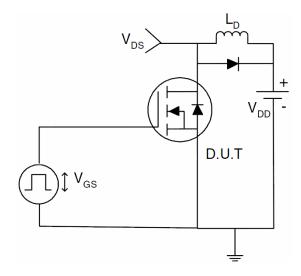
# 1) E<sub>AS</sub> test circuits



## 2) Gate charge test circuit:



# 3) Switch Time Test Circuit:



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# TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure 1. Safe operating area

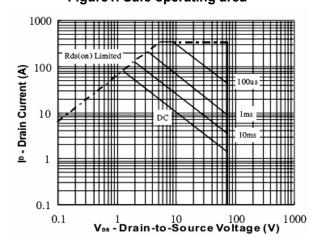


Figure 2. Source-Drain Diode Forward Voltage

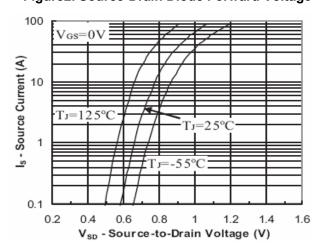


Figure 3. Output characteristics

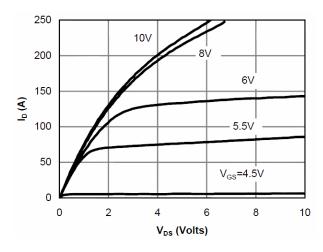


Figure 4. Transfer characteristics

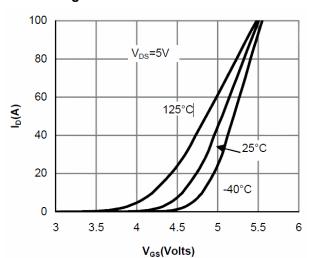


Figure 5. Static drain-source on resistance

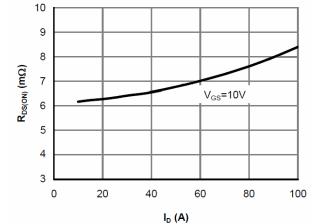
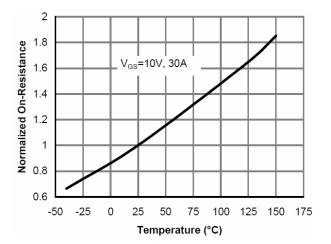


Figure 6. R<sub>DS(ON)</sub> vs Junction Temperature



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Figure 7. BV<sub>DSS</sub> vs Junction Temperature

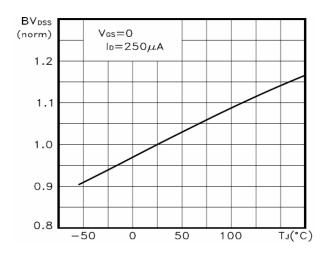


Figure 8. V<sub>GS(th)</sub> vs Junction Temperature

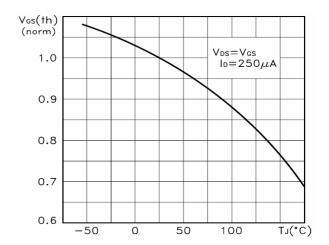


Figure 9. Gate charge waveforms

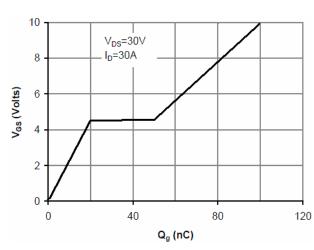
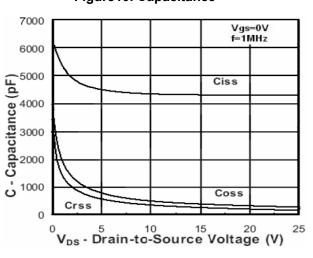
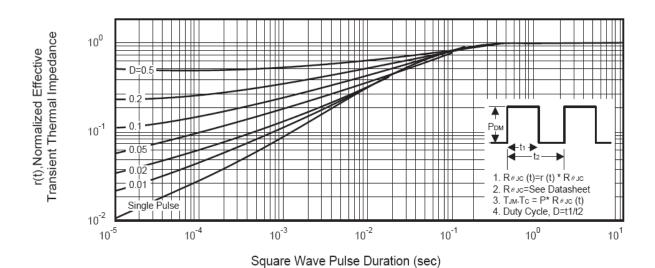


Figure 10. Capacitance

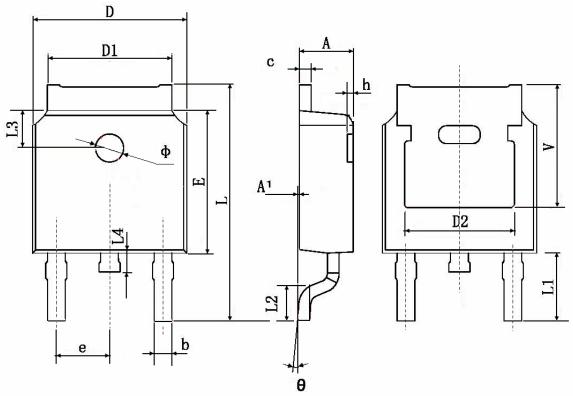




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# **TO-252 Package Information**



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
Α	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	0.483 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.90	0 TYP.	0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 TYP.		0.063 TYP.		
L4	0.600	1.000	0.024	0.039	
Ф	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350 TYP.		0.211	TYP.	

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